

METHOD FOR QUANTIFYING SAFE OPERATING AREA FOR BIPOLAR
JUNCTION TRANSISTOR
Inventor: Kim et al.
Application No. 10/688,550

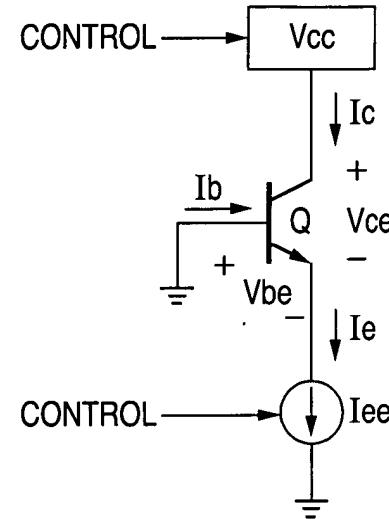
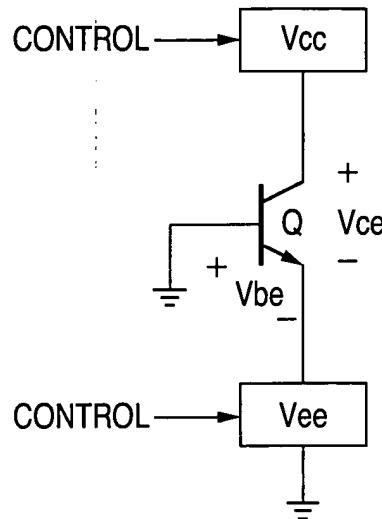


FIG. 1A
(PRIOR ART)

FIG. 2A
(PRIOR ART)

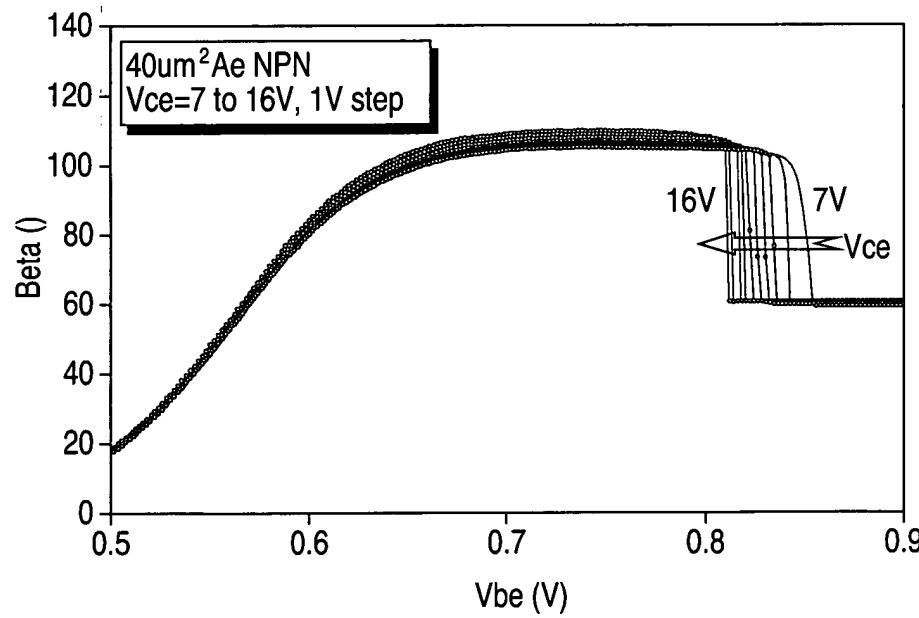


FIG. 1B
(PRIOR ART)

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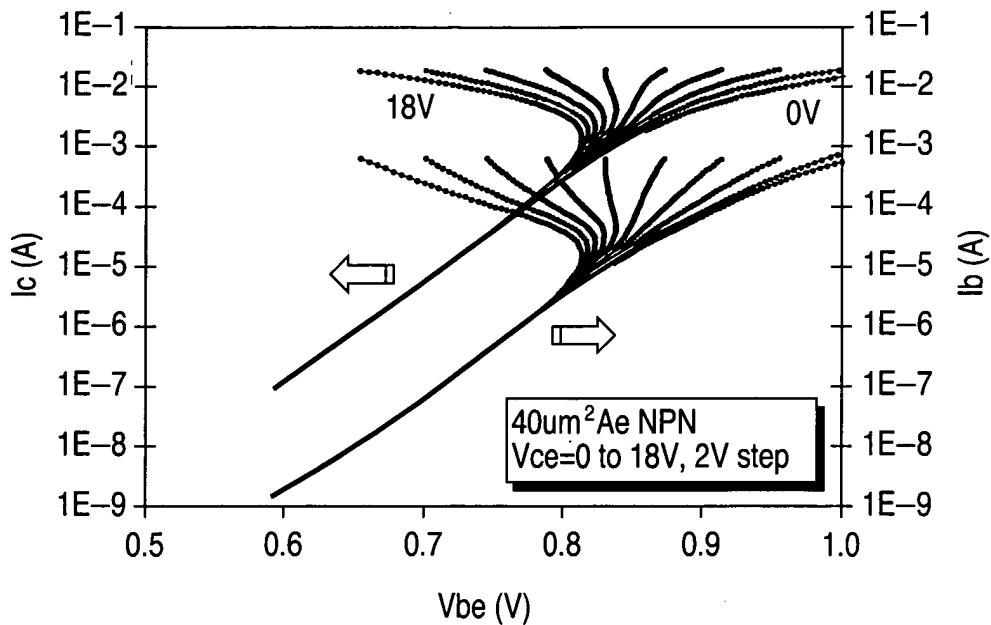


FIG. 2B
(PRIOR ART)

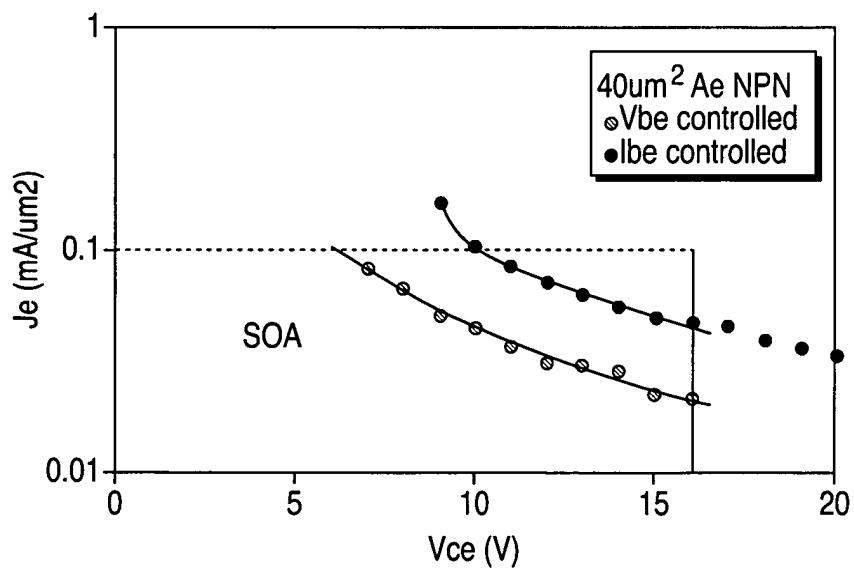


FIG. 3
(PRIOR ART)

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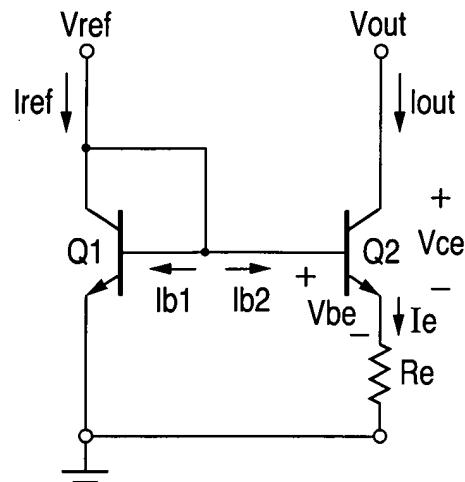


FIG. 4

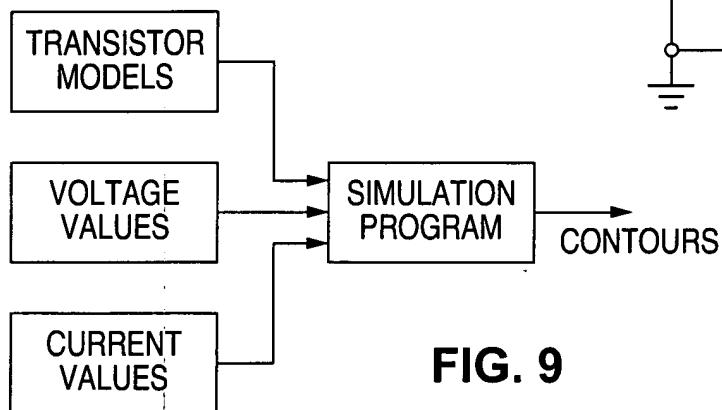


FIG. 9

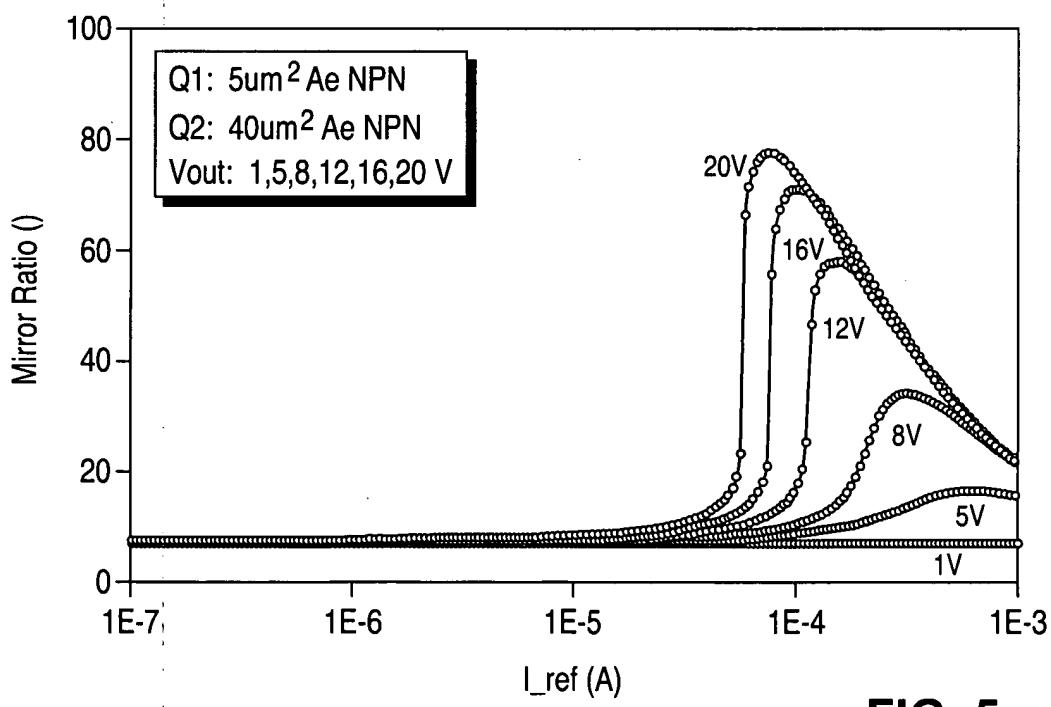


FIG. 5

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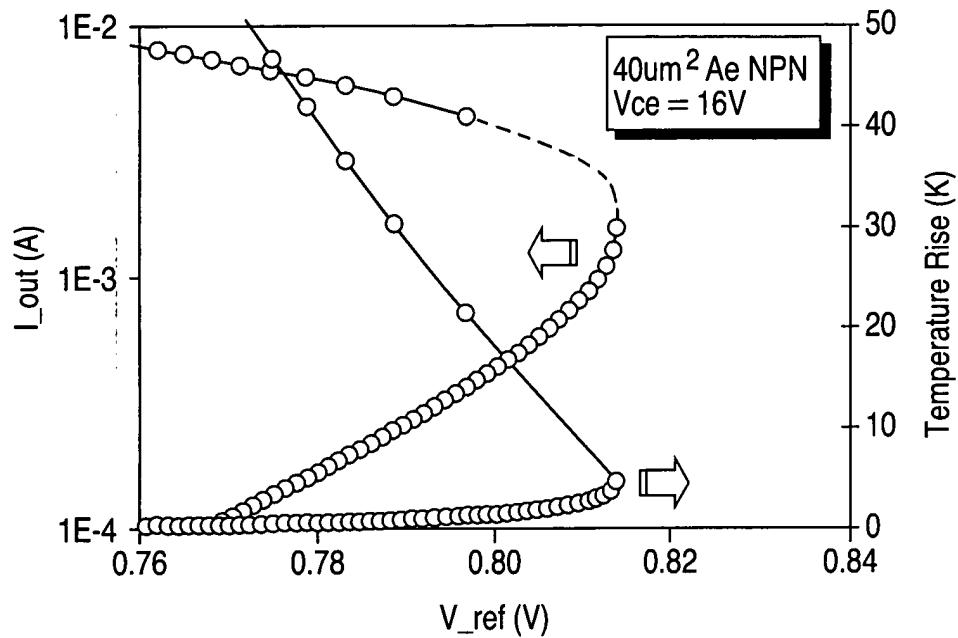


FIG. 6

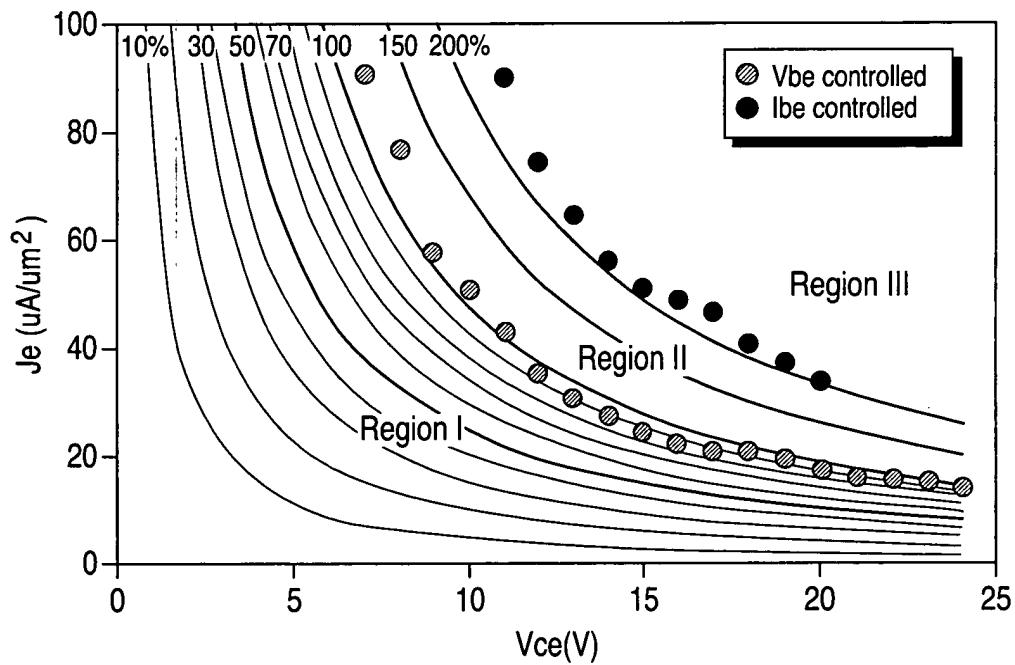


FIG. 8

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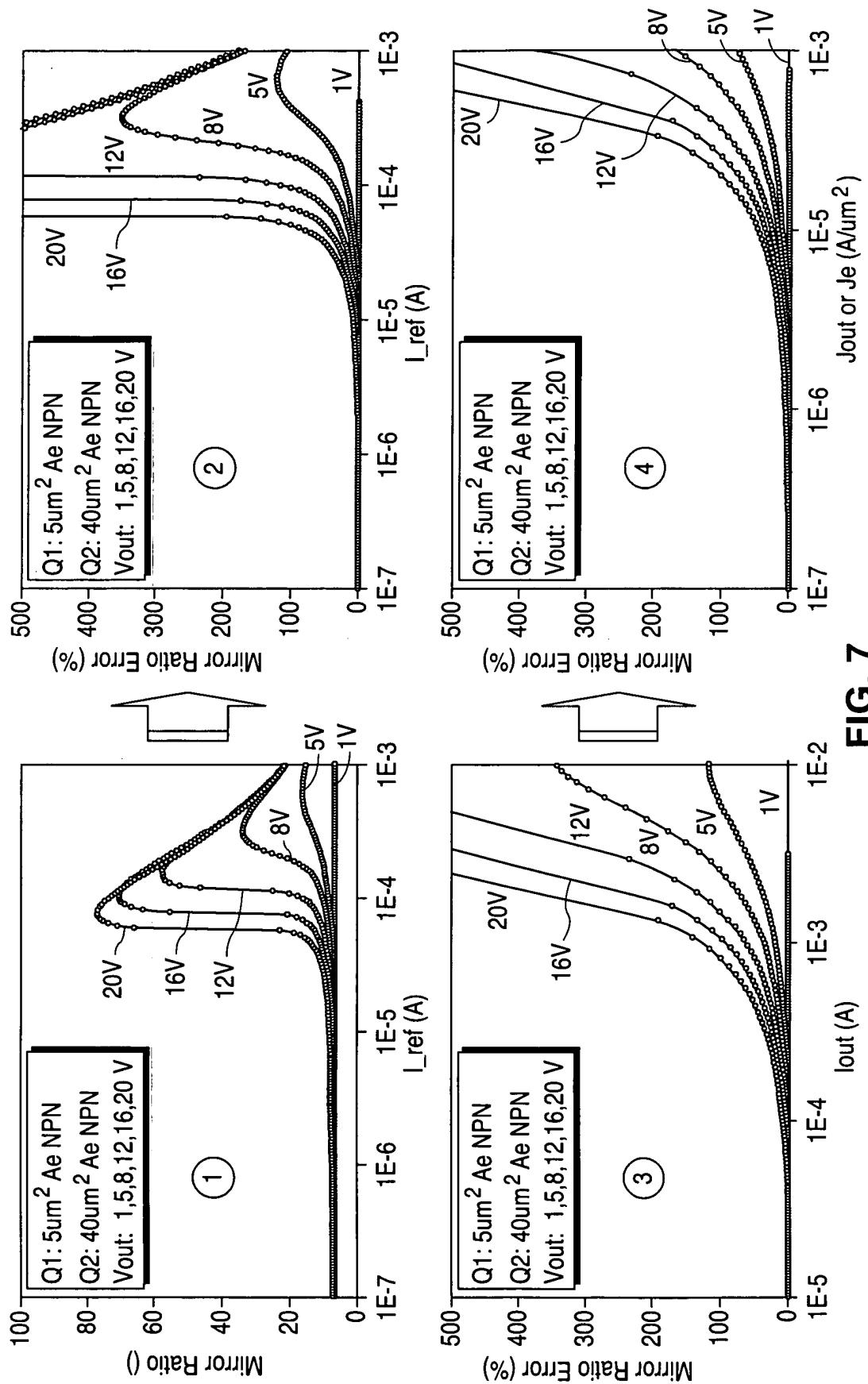


FIG. 7